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Test & Measurement

- sales
- rentals
- calibration
- repair
- disposal

Complimentary Reference Material

This PDF has been made available as a complimentary service for you to assist in evaluating this model for your testing requirements.

TMG offers a wide range of test equipment solutions, from renting short to long term, buying refurbished and purchasing new. Financing options, such as Financial Rental, and Leasing are also available on application.

TMG will assist if you are unsure whether this model will suit your requirements.

Call TMG if you need to organise repair and/or calibrate your unit.

If you click on the "Click-to-Call" logo below, you can all us for FREE!

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Product Lifecycle Management System

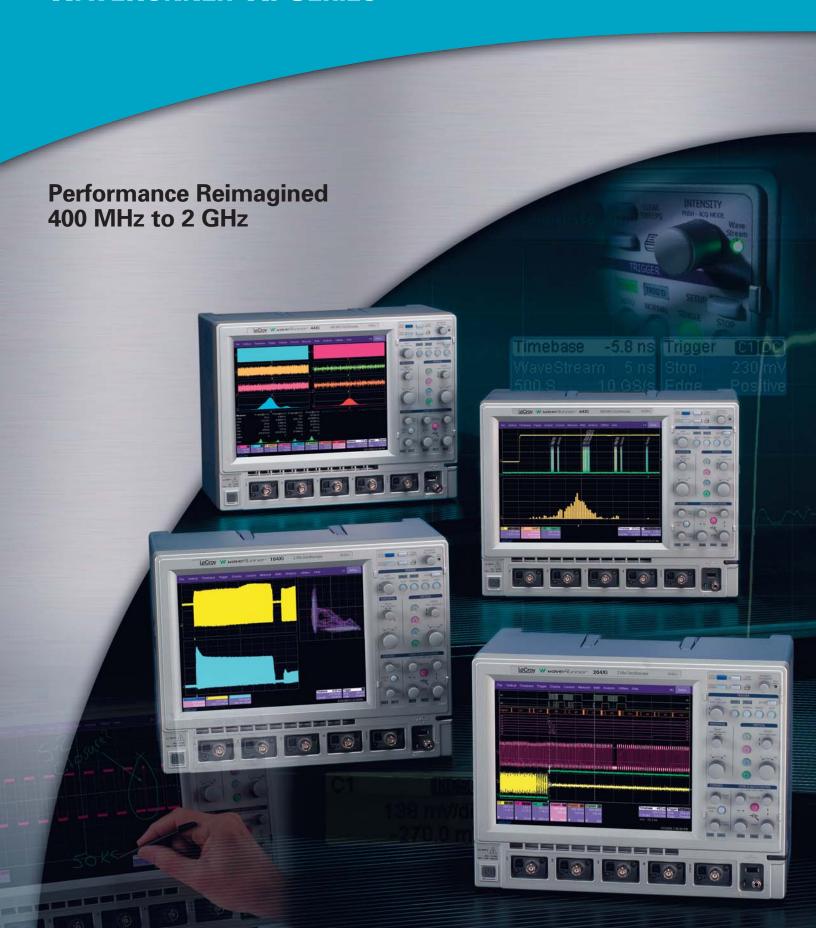






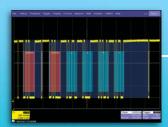
LeCroy

WAVERUNNER® Xi SERIES



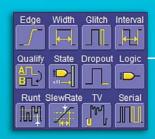
Complete Capability—100% Test Coverage

The LeCroy WaveRunner Xi is the most powerful and capable scope available in its class. Basic system validation using advanced triggers, fast viewing modes, measurement parameters, or serial decodes is simple and easy. Advanced debug, multi-domain analysis, and waveshape analysis are possible with tools unique to WaveRunner Xi. Optional application packages help you make sense of well-defined problems.



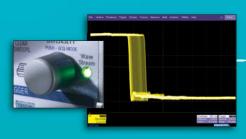
Enhanced Understanding of Serial Data Signals

Trigger on I²C, SPI, UART, RS-232, CAN, or LIN serial data patterns. Intuitively decode values on the oscilloscope grid. Correlate decoded data streams to other events in an embedded control system (optional).



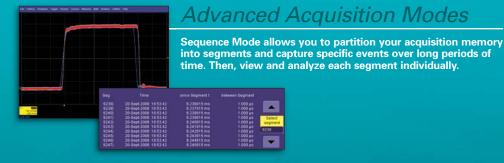
Powerful Triggers Isolate Events

An extensive collection of SMART, Serial, and Digital (MS Series) triggers enables users to quickly and easily isolate events of interest (some optional).



WaveStream[™] Fast Viewing Mode

Use the high sampling rate and WaveStream fast viewing mode to characterize signal shape, rise time, overshoot, etc., and verify the presence or absence of high-speed transients.





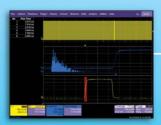


1999



2001

Waverunner-2 raised the bar with higher sample rate, bandwidth, and memory.



WaveScan[™] Advanced Search and Analysis

The best trigger won't find all unusual events—a more powerful capability is needed. WaveScan provides the ability to locate unusual events in a single capture, or scan for an event in many acquisitions over a long period of time using more than 20 different search/scan modes. Use ScanHisto or ScanOverlay to display intuitive scanned results.



Completely Customizable

Quickly create your own measurement parameters or math functions using Excel, MATLAB, Mathcad, or VBScripts (some capability optional).



Advanced Application Packages

Use a variety of application packages to provide detailed, fast solutions for specific problems



2003

Performance boosted again with WaveRunner 6000—10:1 oversampling and 2 Mpt/Ch for 500 MHz oscilloscopes with versions up to 2 GHz.



2005

Engineers vote Big Display/Small Footprint form factor "Best in Test" in *Test & Measurement* magazine (for the WaveSurfer).

Fast Long Memory with Front Panel Zoom Controls

WaveRunner Xi's long memory is optimized for calculation of more information 10–100x faster than other oscilloscopes, while enabling easy access to simple zooming and positioning from the front panel.





Integrated Tool Sets

LeCroy math, measure, and analysis tools are tightly integrated with basic scope operations. It's easy to link capabilities and expand understanding. Free yourself from constraints!

Complete Probing Solutions

A wide variety of active FET probes, current probes, differential probes, HV probes, etc. with complete tip and ground accessories make it easy to probe your signals.

Mixed Signal Oscilloscope Option

The MS Series can capture digital signals with speeds up to 500 MHz. View up to 36 digital channels with up to 50 Mpts/Ch memory and analyze analog and digital events together.

Power/Amplifier Measurements

Excellent overdrive recovery and signal integrity make WaveRunner Xi ideal for high-voltage switching loss, conduction loss, ripple, switching power supply, and other amplifier measurements. Use with LeCroy Differential Amplifiers for high-performance 100,000:1 Common-Mode Rejection Ratio.

Timing Characterization

Extensive triggers allow fast event isolation. Measure timing statistically and view behavior graphically using histograms. Gain real understanding of root cause.

Slow/High-speed Signal Mix

Long memory, HFREJ trigger coupling, builtin noise filtering, etc. enable fast understanding of signal behavior in circuits with a mix of slow-speed (sensor, actuator, power supply, mechanical) and high-speed signals.



Beyond Time Domain Analysis

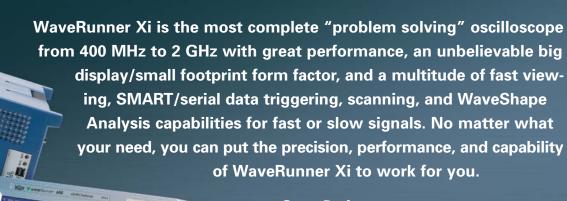
Amplify your understanding with multidomain analysis of your signals. Convert signal information into Statistical domain (Histogram), Spectral domain (long memory FFTs), Jitter, Modulation, or other Measurement Parameter domains (Tracks of measurement parameters). (Some capability is optional.)



2006

WaveRunner Xi combines improved performance with the award-winning form factor of big display and small footprint.





Great Performance

With 5 GS/s and 12.5 Mpts standard on every channel (up to 10 GS/s interleaved with 64Xi, 104Xi, and 204Xi), you can be assured of precise measurements of fast signals, and long captures of slow-speed events.

Big Display/Small Footprint

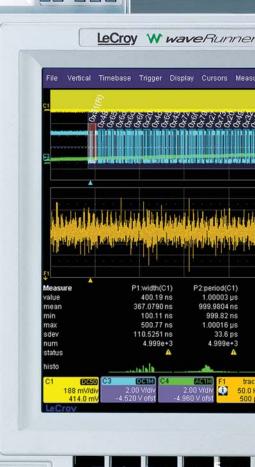
A big display is crucial to understanding circuit behaviors, especially when working with a combination of analog, digital, and serial data signals.

That's why we use a big, bright 10.4" color display to allow room for everything, including time-correlated views of mixed-signal systems and non-time domain analysis. You'll love the impressive display viewing angle; and the very small instrument footprint makes it easy to work anywhere.

Powerful WaveShape Analysis Capability

WaveRunner Xi has the best problem-solving capability, whether you are gathering statistical data on thousands or millions of events, converting signal information into a statistical, modulation, or frequency domain for better understanding, or using WaveScan™ to find anomalous events. In addition, WaveRunner Xi's has numerous application packages to solve specific test and measurement challenges.

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Outstanding Capabilities for Everyday Testing

LeCroy's "out-of-the-box" thinking about oscilloscopes provides a great form factor and no compromises. It's loaded with capability and features that will provide more insight and help you complete your testing faster.

1. Bright, 10.4" Display

You'll never use a small display oscilloscope again. A fantastic viewing angle makes it easy to view.

2. Only 15 cm (6") Deep

The most space-efficient oscilloscope for your bench from 400 MHz to 2 GHz.

3. Dedicated Cursor Knobs

Select type of cursor, position them on your signal, and read values without ever opening a menu.

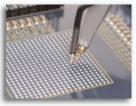
4. Zoom Control Knobs

Four dedicated knobs make it easy to navigate any zoom or math trace without opening menus.

5. Touch Screen with Built-in Stylus

The most time-efficient user interface is even easier to use with a built-in stylus.

6. High Impedance Active Probes



1 GHz and 1.5 GHz active probes with 0.9 pF, 1 M Ω input impedance and an extensive probe tip and ground accessory selection.





Embedded Controller Validation and Debug

LeCroy's powerful WaveRunner Xi oscilloscopes can be turned into high-performance mixed signal oscilloscopes (MSOs) with the addition of the MS-500 or MS-250 mixed signal oscilloscope options. In addition, I²C, SPI, UART, RS-232, LIN, and CAN triggering and decoding options turn the WaveRunner Xi into an all-in-one analog, digital, and serial data trigger, acquisition, and analysis machine.

High-performance Mixed Signal Capabilities

Embedded controller design and debug involves capturing and viewing a number of different types of signals. These signals are typically a mix of analog, digital, and serial data waveforms from a combination of analog sensors, microcontrollers and peripheral devices. With the ability to capture digital signals with speeds up to 500 MHz

and long memory of 50 Mpts/Ch the MS-500 provides unmatched mixed signal performance. For added flexibility the MS-500 supports 36 channels allowing you to view all the signals if a 16 bit micro controller plus some control lines. For applications not requiring the highest performance the MS-250 is a great value, providing 250 MHz maximum signal speed, 18 channels and 10 Mpts/Ch.

File Vertical Timebase Trigger Display Cursors Measure Math Analysis Utilities Help Zoom Communication (Communication) (Commun

Extensive Triggering

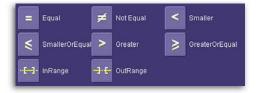
The MS-500 and MS-250 enhance the WaveRunner Xi trigger capabilities. Normal oscilloscope triggers will operate on digital inputs. Cross-Pattern triggering allows for simple or complex trigger patterns to be setup with any combination of analog and digital channels. Event triggering can be configured to arm on an analog signal and trigger on a digital pattern.

Quick Mixed Signal Setup, Easy to Use

Unlike a traditional Logic Analyzer, the MS-500 and MS-250 are easy to use. A simple connection links the oscilloscope with the digital inputs so users can start viewing signals and begin debugging quickly. In addition, all standard oscilloscope tools are readily accessible. Signal debug is simple, using standard oscilloscope tools, such as cursors, measurement parameters, and zooming.

Complete I²C, SPI, UART, RS-232, LIN, and CAN Serial Triggering

Quickly and easily isolate specific serial data events on your embedded controller for better understanding and faster debug. Set up trigger conditions in binary, hexadecimal (Symbolic for CAN) formats. Use the MS-500 or MS-250 to capture serial data busses keeping the analog oscilloscope channels open for other uses. Trigger on DATA in specific locations of long I²C EEPROM reads. Get complete control of your debug process and finish faster.



Powerful Conditional Data Triggering

Completely isolate specific message events for better understanding and debug. Use a conditional I²C, UART, RS-232, or LIN DATA trigger to select a range of DATA values to trigger on, not just a single DATA value. Oftentimes, I²C utilizes DATA bytes to specify sub-addresses for accessing memory



locations in EEPROMs. Conditional DATA trigger allows triggering on a range of DATA bytes that correspond to reads or writes to specific subaddress memory blocks in the EEPROM. It can also aid in monitoring DATA outputs from sensors, such as analog-to-digital converters, and triggering when DATA is outside a safe operating range. In both cases, verifying proper operation becomes a simple task.

Intuitive, Color-Coded Decode Overlay

Advanced software algorithms deconstruct the waveform into binary, hex, or ASCII protocol information, then overlay the decoded data on the waveform.

Various sections of the protocol are color-coded to make it easy to understand. The decode operation is fast—even with long acquisitions.

Table Summary and Search/Zoom

Turn your oscilloscope into a protocol analyzer with the Table display of protocol information. Customize the table, or export Table data to an Excel file. Touch a message in the table and automatically zoom for detail. Search for specific address or data values in the acquisition.

ldx	Time	Addr Length	Address	RW	Length	Data
8	240.494 ms	7	0x21	1	2	0xff 00 00
9	360.555 ms	7	0x21	0	1	0x08
10	360.698 ms		0x21	1	2	0x49 00 00
11	481.865 ms	7	0x21	0	1	0x0a
12	482.007 ms	7	0)(21	1	2	0x00 00 00
13	606.294 ms		0x20	0	3	0x01 36 00
14	721.235 ms	7	0x20	0	1	0×00
15	721.377 ms	7	0x20	1	2	0x123600
16	841.266 ms	7	0x20	0	1	0x02

Excellence in Acquisition

WaveRunner Xi Fast Memory Architecture

LeCroy's proprietary method of data transfer and processing permits wave shapes to be captured and processed 10–100x faster than other oscilloscopes. The result is better capability to perform advanced Waveshape Analysis, and faster debug. With WaveRunner Xi, you'll notice the difference when capturing long records and making measurements, calculating math or FFTs, or performing non-time domain analysis using statistically-based Histograms or parameter-based Tracks.

For instance, in a long 12.5 Mpts capture where it is desired to measure the periodicity of a signal, WaveRunner Xi will

quickly capture and display thousands of signal periods, measure each period, calculate statistics, and display a Histogram of the measurement values. Other oscilloscopes struggle to calculate a single period value (instead of thousands) and cannot provide a Histogram view of the statistical data. Similar speed is achieved during simple operations, such as subtracting two channels (when a differential probe isn't available), or computing FFTs with high-frequency resolution (and, hence, long memory).

SMART Triggers Isolate Events

The WaveRunner Xi oscilloscope provides a multitude of basic and advanced (SMART) triggers to meet any need. Advanced triggers isolate specific events of interest, and (when combined with long memory) provide a complete view of the signal activity around that event. WaveRunner Xi excels in this regard.

Trigger on what you expect (widths, glitches, video, logic patterns, etc.) and also trigger on unusual signals (dropouts, intervals, runts, slew rates). LeCroy's exclusion triggering can exclude normal signals and capture only the abnormal ones, speeding up the debug of your circuits and systems. Trigger on signals down to 1 ns in width (500 ps for width and glitch trigger), or use an "A" condition to qualify a "B" trigger.

Sequence Mode Extends Long Memory and SMART Triggering Capability

Use Sequence mode to store up to 10,000 triggered events as "segments" into oscilloscope memory. This can be ideal when capturing many fast pulses in quick succession (i.e., trigger re-arm time is most important) or when capturing few events separated by long time periods (i.e., longest capture time is most important).

Sequence mode can acquire 4 channels simultaneously, provide timestamps for each acquisition (to 1 ns resolution), minimize capture dead-time (to ≤ 800 ns), and allow various ways to view and analyze the captured segmented data.

Combine sequence mode with an advanced trigger to isolate a rare event, capture all instances over hours or days, and view and analyze each event afterwards.

LeCroy WaveStream[™] Fast Viewing Mode

WaveStream provides a vibrant, intensity graded (256 levels) display with a fast update to closely simulate the look and feel of an analog oscilloscope.



WaveStream
is most helpful
in viewing
signals that
have signal
jitter or signal
anomalies, or

for applying a visual check before creating an advanced trigger or WaveScan setup to locate an unusual event.

Since the sample rate in WaveStream mode can be as high as 10 GS/s (up to 5x that of other oscilloscopes), it is an excellent runt or glitch finder. Timing jitter is often visually assessed to understand approximate behavior.

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WaveStream makes it easy to understand jitter on edges or in eye diagrams. WaveStream also excels in allowing you to relate composite (WaveStream) to single-event (real-time sampled) behaviors. Just capture in WaveStream mode, toggle to view or zoom a single trace, then toggle back to WaveStream mode.

WaveScan[™] Advanced Search and Analysis Finds Problems that Triggers Won't Find.

The best trigger won't find all unusual events—a more powerful capability is sometimes needed. WaveScan provides the ability to locate unusual events in a single capture (i.e., capture and search), or "scan" for an event in many acquisitions over a long period of time. Select from more than 20 search modes (frequency, rise time, runt, duty cycle, etc.), apply a search condition and begin scanning. Since the scanning "modes" are not simply copies of the hardware triggers, the utility and capability is much higher. For instance, there is no "frequency" trigger in any oscilloscope, yet WaveScan allows "frequency" to be quickly "scanned" for. This allows the user to accumulate a data set of unusual events that are separated by hours or days, enabling faster debugging.

When used in multiple acquisitions, WaveScan builds on the traditional LeCroy strength of fast processing of data. A LeCroy X-Stream oscilloscope will quickly "scan" millions of events, looking for unusual occurrences, and do it much faster and more efficiently than other oscilloscopes can.

WaveScan in WaveRunner Xi also contains ScanHisto and ScanOverlay capability. Found events can be overlaid in a ScanOverlay view to provide a quick and simple comparison of events. In addition, measurement-based scanning modes (like the frequency example given above), permit ScanHistograms to show the statistical distribution of the found events. These analysis tools simplify understanding and enable faster debug.



Unmatched Measurement and Validation Capability

WaveRunner Xi provides the highest value for everyday characterization, validation, and debug, and the best capability for quickly debugging advanced problems. Whether you are debugging circuits with a mix of slowand high-speed signals, performing signal integrity checks on high-speed clock and data signals, or doing advanced debugging of complex problems, WaveRunner Xi has the right toolset that is easily applied to the problem.

Oftentimes, only viewing signals does not provide the level of precision that is required for validating designs. At those times, the ability of WaveRunner Xi to quickly provide precise statistical data becomes vital. With WaveRunner Xi, you can quickly accumulate data on thousands of measurements in a single shot (WaveRunner Xi does not limit its measurements to a single value in an acquisition) or in multiple acquisitions. Touch a button, and display statistical information. Touch another button to display a Histicon graphical view of the measurement distribution. Expand this view into a larger histogram of measurement data. Accumulate up to 2 billion measurement events, or create measurable persistence traces of signals with the optional WRXi-STAT.



Advanced Math Characterization

Most oscilloscopes contain only a few simple math functions to subtract waveforms or to perform coarse resolution FFTs on short record length acquisitions. Or, they provide long memory, but limited ability to process the memory and perform WaveShape Analysis

that leads to detailed understanding and faster debug.

WaveRunner Xi oscilloscopes contain dozens of standard math functions, and powerful capabilities, such as long memory FFTs, Trending, Tracking (optional), Sparsing, Interpolation selection, a variety of Persistence Views, user customized math and measurements (MATLAB, Mathcad, or Visual Basic formats), and numerous other specialized capabilities (optional Application Packages). The toolset is rich and deep, and sure to solve any complex problem.

LabNotebook™

A Unique Tool for Documentation and Report Generation

The LabNotebook feature of WaveRunner Xi provides a report generation tool to save and document all your work. Saving all displayed waveforms, relevant WaveRunner Xi settings, and screen images is all done through LabNotebook, eliminating the need to navigate multiple menus to save all these files independently.

The screen images saved can be annotated with freehand notes using the stylus and touch screen, and then included in your report.



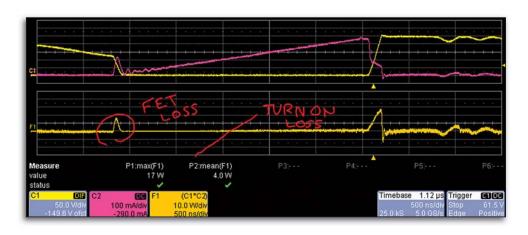
Easy report generation helps you share your findings and communicate important results.

LabNotebook adds a simple way to report your work and save all essential waveforms, settings, and screen images.



Quickly save all the necessary files with LabNotebook in a single button press. Recall your settings from any report by using the Flashback capability.

The WaveRunner Xi touch screen and stylus allow for easy annotation of the screen. LabNotebook allows you to add freehand text and graphics in multiple colors along with printed text and arrows to help identify important parts of your waveforms and measurements.



Multidomain WaveShape Analysis Improves Understanding

The most difficult electrical circuit problems are rarely obvious in the time domain. Long memory with zooming, searching, and scanning is an important part of the solution. However, serious design professionals understand the importance of converting time-domain information into statistical, parameter, or frequency domains so as to get to the root of the problem quicker. WaveRunner Xi provides you with the tools necessary to understand complex circuit problems and solve them faster.

Trend Views Turn Your Oscilloscope Into a Strip Chart Recorder

Slowly sample at 1000 seconds/div to capture hours of slow speed signal data. Using Trend Views, plot measurement values of high-speed signals with slower speed signals, such as transducer or voltage values.

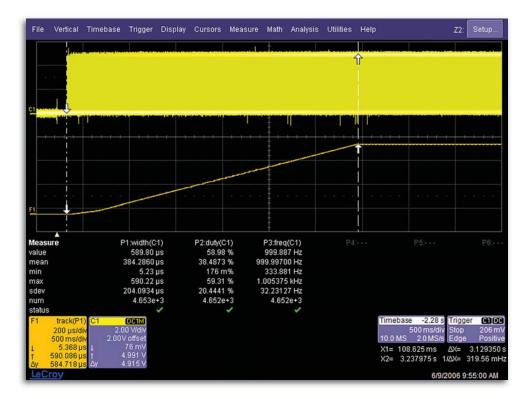
Track Views Provide Graphical Display of Parameter Values vs. Time

Track in WaveRunner Xi (optional) uses every instance of a measurement in an acquisition to create a plot of measurement values on the Y-axis and time on the X-axis. The result is a graphical plot of a measurement

change time-correlated to the original channel acquisition—perfect for intuitive understanding.

Some examples include:

- Measuring a signal's Frequency over a 100 ms interval, and understanding whether the correct frequency shifts are present at the right times.
- Measuring a pulse width modulated (PWM) signal's Width over a 1 second interval, and determining if the modulation circuit is correctly reacting to system changes.
- Measuring the cycle-cycle jitter values in a micro processor and understanding how cycle-cycle jitter peaks correlate to spikes in power supply lines.



The PWM signal for a power tool motor speed controller is monitored during start-up. The Width parameter is used. All instances of Width during the acquisition are measured. Then, Track was applied to determine when the speed plateaued (i.e., when the tool rotation reached steady-state).

Histograms Graphically Present Statistical Data

LeCroy oscilloscopes excel in capturing hundreds or thousands times more measurements per acquisition than other oscilloscopes do. With this much data, it is essential to provide more than just a list of mean, min, max, sdev, etc. Histograms provide an intuitive way to view the distribution of statistical data and gain real insight into underlying problems. For instance:

- Measure millions of jitter values in seconds, understand whether the measurement distribution is Gaussian or non-Gaussian, and correct timing problems to stay within a timing budget.
- Improve validation of timing budgets when measuring embedded controller response times. Measure hundreds of thousands of timing events instead of just hundreds, and easily view real-world worst-case timing situations.



A 200 MHz clock signal is acquired at 10 GS/s using 20 Mpts of acquisition data (400,000 cycles). Cycle-Cycle and Period Jitter are measured and analyzed with Tracks and Histograms. Cycle-Cycle jitter shows a distinctive modality. Other signals could now be acquired and time-correlated to understand the histogram modality.

Fast Fourier Transforms (FFTs) Provide Spectral Views for Advanced Troubleshooting

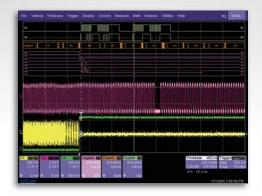
LeCroy's long memory (up to 25 Mpts) FFTs increase your ability to understand signal behaviors in the frequency domain. The long memory allows users to obtain 5–100x the frequency resolution possible with FFTs available in other oscilloscopes, which allows more precise troubleshooting. Built-in averaging of FFTs helps to eliminate random events from the calculations. In addition, LeCroy FFTs can be applied to any channel or math function, which greatly expands the ability to gather useful information.

Some examples include:

- Capture power supply, clock, and data signals with 1 kHz frequency resolution. Correlate power supply noise to signal integrity.
- Apply an FFT to a Track of Cycle-Cycle Jitter and gain insight into the frequency components and root cause of the jitter.
- Quickly capture hundreds of acquisitions and average the FFTs to increase frequency signal-noise ratio and to separate random from deterministic events.

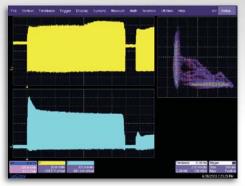
Specific Solutions for Tough Problems

In addition to the general purpose waveshape analysis tools that LeCroy offers with WaveRunner Xi, there are also specific tool sets that are packaged into a complete Application solution for Automotive, Embedded Design, or Switching Power Supply markets. These packages offer great value, and allow you to add to your oscilloscope over time as your needs change.



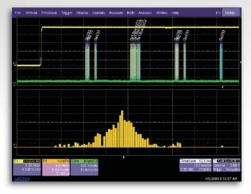
Mixed Signal Testing (MS Series Options)

Add high performance mixed-signal capability to any WaveRunner Xi with the MS-500 or MS-250. These solutions can capture digital signals with speeds up to 500 MHz. Available in 18 or 36 digital channel models and with long 50 Mpts/Ch memory the MS series are the ideal tools for efficient testing 16 bit embedded systems where all 16 ADDR and DATA lines can be viewed simultaneously.



PowerMeasure Analysis Software Package (PMA2)

The PMA2 software package enhances your ability to analyze power conversion devices and circuits. Measure switching and conduction losses with high accuracy. Capture power supply start-up events using long memory, view changes in the PWM signals using Track, and correlate PWM changes to other circuit signals. Measure power frequency harmonics and apparent/real power and power factor. Optional accessories, such as differential amplifiers, differential probes, current probes, and deskew fixtures complete the solution.



CANbus Trigger, Decode, and Measure/Graph Testing Options (CANbus TDM, CANbus TD, Vehicle Bus Analyzers)

Flexibly trigger on CAN bus messages. Decode and display hexadecimal data values next to the CAN signal on the screen. Use CAN-specific parameters to automatically measure timing from sensor or actuator signals to specific CAN messages. Statistically analyze performance with histograms, and determine root cause of timing irregularities. Extract decimal data from a CAN message and graph it as if it were an analog signal. Easily correlate electrical problems to CAN bus messages or error frame data. In addition, Vehicle Bus Analyzers (VBAs) provide CAN symbolic level trigger and decode on up to four different CAN buses.



Electromagnetic Compatibility Software Package (EMC)

The EMC software package adds flexibility to the rise time, fall time, and width parameters necessary to accurately measure ESD pulses, EFT bursts, surges, and transients common in EMC testing. In addition, the EMC package allows histogramming of up to 2 billion events, parameter math, and measurement filtering. Combine this with LeCroy's unbeatable standard statistics and measurement capability and you have a winning combination.



Jitter and Timing Analysis Software Package (JTA2)

Use specialized timing parameters to measure period, cycle-cycle, half period, width, etc. jitter on a variety of signals. Use the three views of jitter (statistical, time, and frequency) to understand root cause and to debug problems. Histograms (statistical view) provide understanding of statistical distributions. Tracks (time view) provide a means to show time-correlated peaks or modulations of jitter, and to compare it to other signals. FFTs (frequency view) provide the ability to debug root causes of high in-circuit jitter.



Digital Filter Software Package (DFP2)

DFP2 lets you implement Finite or Infinite Impulse Response filters to eliminate undesired spectral components, such as noise, and enhances your ability to examine important signal components. The DFP2 option allows you to choose from a standard set of FIR or IIR filters and also gives you the ability to design your own filters.

Probes

High-performance probes are an essential tool for accurate signal capture. Consequently LeCroy offers an extensive range of probes to meet virtually every application need. Optimized for use with LeCroy oscilloscopes, these probes set new standards for responsiveness and signal detection.

ZS Series High Impedance Active Probes

Leading Features:

- 1 GHz (ZS1000) and 1.5 GHz (ZS1500) bandwidths
- High Impedance (0.9 pF, 1 M Ω)
- Extensive standard and available probe tip and ground connection accessories
- ±12 Vdc offset (ZS1500)
- LeCroy ProBus system

ADP305, ADP300

Leading Features:

- 20 MHz and 100 MHz bandwidth
- 1,000 V_{rms} common mode voltage
- 1,400 V_{peak} differential voltage
- EN 61010 CAT III
- 80 dB CMRR at 50/60 Hz
- LeCroy ProBus system only

PPE1.2KV, PPE2KV, PPE4KV, PPE5KV, PPE6KV, PPE20KV

Leading Features:

- Suitable for safe, accurate high-voltage measurements
- 1.2 kV to 20 kV
- ullet Works with any 1 M Ω input oscilloscope





CP030 and CP031

Leading Features:

- 30 A_{rms} continuous current
- 50 or 100 MHz bandwidth
- Measure pulses up to 50 A_{peak}
- Small form factor accommodates large conductors with small jaw size
- LeCroy ProBus system

AP031

Leading Features:

- Lowest priced differential probe
- 15 MHz bandwidth
- 700 V maximum input voltage
- Works with any 1 M Ω input oscilloscope

AP033 and AP034

Leading Features:

- 500 MHz and 1 GHz Bandwidth
- 10,000:1 CMRR
- Wide dynamic range, low noise
- LeCroy ProBus System

HFP2500

Leading Features:

- 2.5 GHz bandwidth, 0.7 pF input capacitance
- Interchangeable tips for a variety of probing needs
- Hands free probing with probe holder
- AutoColor ID matches probe color to channel
- LeCroy ProBus system





Specifications

Standard

Math Tools

Display up to four math function traces (F1-F4). The easy-to-use graphical interface simplifies setup of up to two operations on each function trace; and function traces can be chained together to perform math-on-math.

absolute value integral average (summed) invert (negate) log (base e) average (continuous) custom (MATLAB, Mathcad, log (base 10) VBScript) - limited points product (x) ratio (/) derivative deskew (resample) reciprocal difference (-) rescale (with units)

enhanced resolution (to 11 bits vertical) roof
envelope (sinx)/x
exp (base e) square
exp (base 10) square root
fft (power spectrum, magnitude, phase, sum (+)

up to 50 kpts) trend (datalog) of 1000 events

or zoom (identity)

Measure Tools

histogram of 1000 events

Display any 6 parameters together with statistics, including their average, high, low, and standard deviations. Histicons provide a fast, dynamic view of parameters and wave-shape characteristics.

amplitude frequency risetime (10-90%, 20-80%, @ level) area last level @ x rms base std. deviation cycles maximum time @ level custom (MATLAB, mean Mathcad, VBScript) ton median limited points Δ time @ level minimum delay Δ time @ level from number of points

number of points Δ time @ level fr Δ delay +overshoot trigger width (positive + negative) talltime (90–10%, 80–20%, @ level) phase Δ time @ level fr Δ time @

Pass/Fail Testing

first

Simultaneously test multiple parameters against selectable parameter limits or pre-defined masks. Pass or fail conditions can initiate actions including document to local or networked files, e-mail the image of the failure, save waveforms, send a pulse out at the rear panel auxiliary BNC output, or (with the GPIB option) send a GPIB SRQ.

Software Options-Advanced Math and WaveShape Analysis

Statistics Package (WRXi-STAT)

This package provides additional capability to statistically display measurement information and to analyze results:

- Histograms expanded with 19 histogram parameters/up to 2 billion events.
- Persistence Histogram
- Persistence Trace (mean, range, sigma)

Master Analysis Software Package (WRXi-XMAP)

This package provides maximum capability and flexibility, and includes all the functionality present in XMATH, XDEV, and JTA2

Advanced Math Software Package (WRXi-XMATH)

This package provides a comprehensive set of WaveShape Analysis tools providing insight into the wave shape of complex signals. Includes:

- Parameter math add, subtract, multiply, or divide two different parameters.
 Invert a parameter and rescale parameter values.
- Histograms expanded with 19 histogram parameters/up to 2 billion events.
- Trend (datalog) of up to 1 million events
- Track graphs of any measurement parameter.
- FFT capability includes: power averaging, power density, real and imaginary components, frequency domain parameters, and FFT on up to 24 Mpts.
- Narrow-band power measurements
- Auto-correlation function
- Sparse function
- Cubic interpolation function

Advanced Customization Software Package (WRXi-XDEV)

This package provides a set of tools to modify the scope and customize it to meet your unique needs. Additional capability provided by XDEV includes:

- Creation of your own measurement parameter or math function, using third-party software packages, and display of the result in the scope. Supported third-party software packages include:
 - VBScript MATLAB Excel Mathcad
- CustomDSO create your own user interface in a scope dialog box.
- Addition of macro keys to run VBScript files
- Support for plug-ins

Value Analysis Software Package (WRXi-XVAP)

Measurements:

 Jitter and Timing parameters (period@level,width@level, edge@level, duty@level, time interval error@level, frequency@level, half period, setup, skew, Δ period@level, Δ width@level).

Math:

- Persistence histogram Persistence trace (mean, sigma, range)
- 1 Mpts FFTs with power spectrum density, power averaging, real, imaginary, and real+imaginary settings)

Statistical and Graphical Analysis

- 1 Mpts Trends and Histograms 19 histogram parameters
- Track graphs of any measurement parameter

Intermediate Math Software Package (WRXi-XWAV)

Math:

 1 Mpts FFTs with power spectrum density, power averaging, real, and imaginary components

Statistical and Graphical Analysis

- 1 Mpts Trends and Histograms
- 19 histogram parameters
- Track graphs of any measurement parameter

Specifications

Vertical System	WaveRunner 44Xi	WaveRunner 64Xi	WaveRunner 62Xi	WaveRunner 104Xi	WaveRunner 204Xi
Nominal Analog Bandwidth @ 50 Ω, 10 mV-1 V/div	400 MHz	600 MHz	600 MHz	1 GHz	2 GHz
Rise Time (Typical)	875 ps	625 ps	625 ps	400 ps	225 ps
Input Channels	4	4	2	4	4
Bandwidth Limiters	20 MHz; 200 MHz				
Input Impedance	1 MΩ 16 pF or 5	0 Ω		1 MΩ 20 pF or 5	0 Ω
Input Coupling	50 Ω: DC, 1 MΩ: /	AC, DC, GND			
Maximum Input Voltage	50 Ω: 5 V _{rms} , 1 M: (DC + Peak AC ≤ !			50Ω : $5 V_{rms}$, $1 MΩ$ (DC + Peak AC ≤ 1	
Vertical Resolution		th enhanced resolution	on (ERES)		
Sensitivity	50 Ω: 2 mV/div–1	V/div fully variable; 1	MΩ: 2 mV-10 V/div fu	lly variable	
DC Accuracy			ull scale, ≥ 10 mV/div		
Offset Range		nV/div, ±10 V @ 100 mV 3 mV/div, ±10 V @ 100 v–10 V/div			100 mv-1 V/div,
Input Connector	ProBus/BNC				
Timebase System					
Timebases			channels; an external c		
Time/Division Range	Real time: 200 ps/	div-10 s/div, RIS mod	le: 200 ps/div to 10 ns	/div, Roll mode: up to	1,000 s/div
Clock Accuracy	≤ 5 ppm @ 25 °C	typical) (≤ 10 ppm @	5–40 °C)		
Sample Rate and Delay Time Accuracy	Equal to Clock Acc	curacy			
Channel to Channel Deskew Range	±9 x time/div setti	ng, 100 ms max., ead	ch channel		
External Sample Clock	DC to 600 MHz: ([OC to 1 GHz for 104X	i and 204Vi) 50 O. /lim	ited DIM in 1 May DA	NC input, limited to 2 Ch
·			time and amplitude re		
Roll Mode	operation (1 Ch in		time and amplitude re		
Acquisition System	operation (1 Ch in User selectable at 44Xi	62Xi), (minimum rise ≥ 500 ms/div and ≤ 1 64Xi	time and amplitude re 00 kS/s 62Xi	quirements apply at l	ow frequencies) 204Xi
Acquisition System Single-Shot Sample Rate/Ch	operation (1 Ch in User selectable at 44Xi 5 GS/s	62Xi), (minimum rise ≥ 500 ms/div and ≤ 1 64Xi 5 GS/s	time and amplitude re 00 kS/s 62Xi 5 GS/s	nquirements apply at least apply apply	204Xi 5 GS/s
Acquisition System Single-Shot Sample Rate/Ch Interleaved Sample Rate (2 Ch)	operation (1 Ch in User selectable at 44Xi 5 GS/s 5 GS/s	62Xi), (minimum rise ≥ 500 ms/div and ≤ 1 64Xi	time and amplitude re 00 kS/s 62Xi	quirements apply at l	ow frequencies) 204Xi
Acquisition System Single-Shot Sample Rate/Ch	operation (1 Ch in User selectable at 44Xi 5 GS/s 5 GS/s 200 GS/s	62Xi), (minimum rise ≥ 500 ms/div and ≤ 1 64Xi 5 GS/s 10 GS/s	time and amplitude re 00 kS/s 62Xi 5 GS/s 10 GS/s	nquirements apply at least apply apply	204Xi 5 GS/s
Acquisition System Single-Shot Sample Rate/Ch Interleaved Sample Rate (2 Ch) Random Interleaved Sampling (RIS) RIS Mode	operation (1 Ch in User selectable at 44Xi 5 GS/s 5 GS/s 200 GS/s User selectable from	62Xi), (minimum rise ≥ 500 ms/div and ≤ 1 64Xi 5 GS/s 10 GS/s 200 ps/div to 10 n	time and amplitude re 00 kS/s 62Xi 5 GS/s 10 GS/s	104Xi 5 GS/s 10 GS/s	204Xi 5 GS/s 10 GS/s
Acquisition System Single-Shot Sample Rate/Ch Interleaved Sample Rate (2 Ch) Random Interleaved Sampling (RIS)	operation (1 Ch in User selectable at 44Xi 5 GS/s 5 GS/s 200 GS/s	62Xi), (minimum rise ≥ 500 ms/div and ≤ 1 64Xi 5 GS/s 10 GS/s 200 ps/div to 10 n	time and amplitude re 00 kS/s 62Xi 5 GS/s 10 GS/s	104Xi 5 GS/s 10 GS/s	204Xi 5 GS/s 10 GS/s
Acquisition System Single-Shot Sample Rate/Ch Interleaved Sample Rate (2 Ch) Random Interleaved Sampling (RIS) RIS Mode	operation (1 Ch in User selectable at 44Xi 5 GS/s 5 GS/s 200 GS/s User selectable from	62Xi), (minimum rise ≥ 500 ms/div and ≤ 1 64Xi 5 GS/s 10 GS/s 200 ps/div to 10 n	time and amplitude re 00 kS/s 62Xi 5 GS/s 10 GS/s	104Xi 5 GS/s 10 GS/s	204Xi 5 GS/s 10 GS/s
Acquisition System Single-Shot Sample Rate/Ch Interleaved Sample Rate (2 Ch) Random Interleaved Sampling (RIS) RIS Mode Trigger Rate (Maximum) Sequence Time Stamp Resolution Minimum Time Between	operation (1 Ch in User selectable at 44Xi 5 GS/s 5 GS/s 200 GS/s User selectable from 1,250,000 wavefor	62Xi), (minimum rise ≥ 500 ms/div and ≤ 1 64Xi 5 GS/s 10 GS/s 200 ps/div to 10 n	time and amplitude re 00 kS/s 62Xi 5 GS/s 10 GS/s	104Xi 5 GS/s 10 GS/s	204Xi 5 GS/s 10 GS/s
Acquisition System Single-Shot Sample Rate/Ch Interleaved Sample Rate (2 Ch) Random Interleaved Sampling (RIS) RIS Mode Trigger Rate (Maximum) Sequence Time Stamp Resolution Minimum Time Between Sequential Segments	operation (1 Ch in User selectable at 44Xi 5 GS/s 5 GS/s 200 GS/s User selectable from 1,250,000 wavefor 1 ns 800 ns	62Xi), (minimum rise ≥ 500 ms/div and ≤ 1 64Xi 5 GS/s 10 GS/s 200 ps/div to 10 n rms/second	time and amplitude re 00 kS/s 62Xi 5 GS/s 10 GS/s s/div	104Xi 5 GS/s 10 GS/s User selectable from	204Xi 5 GS/s 10 GS/s m 100 ps/div to 10 ns/div
Acquisition System Single-Shot Sample Rate/Ch Interleaved Sample Rate (2 Ch) Random Interleaved Sampling (RIS) RIS Mode Trigger Rate (Maximum) Sequence Time Stamp Resolution Minimum Time Between	operation (1 Ch in User selectable at 44Xi 5 GS/s 5 GS/s 200 GS/s User selectable from 1,250,000 wavefor 1 ns 800 ns Max. Acquisition F	62Xi), (minimum rise ≥ 500 ms/div and ≤ 1 64Xi 5 GS/s 10 GS/s 200 ps/div to 10 n	time and amplitude re 00 kS/s 62Xi 5 GS/s 10 GS/s s/div	104Xi 5 GS/s 10 GS/s	204Xi 5 GS/s 10 GS/s m 100 ps/div to 10 ns/div
Acquisition System Single-Shot Sample Rate/Ch Interleaved Sample Rate (2 Ch) Random Interleaved Sampling (RIS) RIS Mode Trigger Rate (Maximum) Sequence Time Stamp Resolution Minimum Time Between Sequential Segments	operation (1 Ch in User selectable at 44Xi 5 GS/s 5 GS/s 200 GS/s User selectable from 1,250,000 wavefor 1 ns 800 ns	62Xi), (minimum rise ≥ 500 ms/div and ≤ 1 64Xi 5 GS/s 10 GS/s om 200 ps/div to 10 n rms/second	time and amplitude re 00 kS/s 62Xi 5 GS/s 10 GS/s s/div	104Xi 5 GS/s 10 GS/s User selectable fro Segments (Sequel 10,000	204Xi 5 GS/s 10 GS/s m 100 ps/div to 10 ns/div nce Mode)
Acquisition System Single-Shot Sample Rate/Ch Interleaved Sample Rate (2 Ch) Random Interleaved Sampling (RIS) RIS Mode Trigger Rate (Maximum) Sequence Time Stamp Resolution Minimum Time Between Sequential Segments Acquisition Memory Options Standard Acquisition Processing	operation (1 Ch in User selectable at 44Xi 5 GS/s 5 GS/s 200 GS/s User selectable from 1,250,000 wavefor 1 ns 800 ns Max. Acquisition F 12.5M/25M 44Xi	62Xi), (minimum rise ≥ 500 ms/div and ≤ 1 64Xi 5 GS/s 10 GS/s om 200 ps/div to 10 n rms/second Points (4 Ch/2 Ch, 2 C	time and amplitude re 00 kS/s 62Xi 5 GS/s 10 GS/s s/div h/1 Ch in 62Xi)	104Xi 5 GS/s 10 GS/s User selectable fro Segments (Sequel 10,000) 104Xi	204Xi 5 GS/s 10 GS/s m 100 ps/div to 10 ns/div nce Mode) 204Xi
Acquisition System Single-Shot Sample Rate/Ch Interleaved Sample Rate (2 Ch) Random Interleaved Sampling (RIS) RIS Mode Trigger Rate (Maximum) Sequence Time Stamp Resolution Minimum Time Between Sequential Segments Acquisition Memory Options Standard Acquisition Processing Time Resolution (min, Single-shot)	operation (1 Ch in User selectable at 44Xi 5 GS/s 5 GS/s 200 GS/s User selectable fro 1,250,000 wavefo 1 ns 800 ns Max. Acquisition F 12.5M/25M 44Xi 200 ps (5 GS/s)	62Xi), (minimum rise ≥ 500 ms/div and ≤ 1 64Xi 5 GS/s 10 GS/s om 200 ps/div to 10 n rms/second Points (4 Ch/2 Ch, 2 C 64Xi 100 ps (10 GS/s)	time and amplitude re 00 kS/s 62Xi 5 GS/s 10 GS/s s/div h/1 Ch in 62Xi) 62Xi 100 ps (10 GS/s)	104Xi 5 GS/s 10 GS/s User selectable fro Segments (Sequel 10,000	204Xi 5 GS/s 10 GS/s m 100 ps/div to 10 ns/div nce Mode)
Acquisition System Single-Shot Sample Rate/Ch Interleaved Sample Rate (2 Ch) Random Interleaved Sampling (RIS) RIS Mode Trigger Rate (Maximum) Sequence Time Stamp Resolution Minimum Time Between Sequential Segments Acquisition Memory Options Standard Acquisition Processing Time Resolution (min, Single-shot) Averaging	operation (1 Ch in User selectable at 44Xi 5 GS/s 5 GS/s 200 GS/s User selectable fro 1,250,000 wavefo 1 ns 800 ns Max. Acquisition F 12.5M/25M 44Xi 200 ps (5 GS/s) Summed and cont	62Xi), (minimum rise ≥ 500 ms/div and ≤ 1 64Xi 5 GS/s 10 GS/s 200 ps/div to 10 n rms/second Points (4 Ch/2 Ch, 2 C 64Xi 100 ps (10 GS/s) cinuous averaging to 1	time and amplitude re 00 kS/s 62Xi 5 GS/s 10 GS/s s/div h/1 Ch in 62Xi) 62Xi 100 ps (10 GS/s)	104Xi 5 GS/s 10 GS/s User selectable fro Segments (Sequel 10,000) 104Xi	204Xi 5 GS/s 10 GS/s m 100 ps/div to 10 ns/div nce Mode) 204Xi
Acquisition System Single-Shot Sample Rate/Ch Interleaved Sample Rate (2 Ch) Random Interleaved Sampling (RIS) RIS Mode Trigger Rate (Maximum) Sequence Time Stamp Resolution Minimum Time Between Sequential Segments Acquisition Memory Options Standard Acquisition Processing Time Resolution (min, Single-shot) Averaging ERES	operation (1 Ch in User selectable at 44Xi 5 GS/s 5 GS/s 200 GS/s User selectable fro 1,250,000 wavefo 1 ns 800 ns Max. Acquisition F 12.5M/25M 44Xi 200 ps (5 GS/s) Summed and cont From 8.5 to 11 bit	62Xi), (minimum rise ≥ 500 ms/div and ≤ 1 64Xi 5 GS/s 10 GS/s om 200 ps/div to 10 n rms/second Points (4 Ch/2 Ch, 2 C 64Xi 100 ps (10 GS/s) cinuous averaging to 1 s vertical resolution	time and amplitude re 00 kS/s 62Xi 5 GS/s 10 GS/s s/div h/1 Ch in 62Xi) 62Xi 100 ps (10 GS/s) million sweeps	104Xi 5 GS/s 10 GS/s User selectable fro Segments (Sequel 10,000) 104Xi	204Xi 5 GS/s 10 GS/s m 100 ps/div to 10 ns/div nce Mode) 204Xi
Acquisition System Single-Shot Sample Rate/Ch Interleaved Sample Rate (2 Ch) Random Interleaved Sampling (RIS) RIS Mode Trigger Rate (Maximum) Sequence Time Stamp Resolution Minimum Time Between Sequential Segments Acquisition Memory Options Standard Acquisition Processing Time Resolution (min, Single-shot) Averaging ERES Envelope (Extrema)	operation (1 Ch in User selectable at 44Xi 5 GS/s 5 GS/s 200 GS/s User selectable from 1,250,000 wavefor 1 ns 800 ns Max. Acquisition From 8.5 GS/s Summed and continued from 8.5 to 11 bit Envelope, floor, or	62Xi), (minimum rise ≥ 500 ms/div and ≤ 1 64Xi 5 GS/s 10 GS/s 200 ps/div to 10 n rms/second Points (4 Ch/2 Ch, 2 C 64Xi 100 ps (10 GS/s) cinuous averaging to 1	time and amplitude re 00 kS/s 62Xi 5 GS/s 10 GS/s s/div h/1 Ch in 62Xi) 62Xi 100 ps (10 GS/s) million sweeps	104Xi 5 GS/s 10 GS/s User selectable fro Segments (Sequel 10,000) 104Xi	204Xi 5 GS/s 10 GS/s m 100 ps/div to 10 ns/div nce Mode) 204Xi
Acquisition System Single-Shot Sample Rate/Ch Interleaved Sample Rate (2 Ch) Random Interleaved Sampling (RIS) RIS Mode Trigger Rate (Maximum) Sequence Time Stamp Resolution Minimum Time Between Sequential Segments Acquisition Memory Options Standard Acquisition Processing Time Resolution (min, Single-shot) Averaging ERES Envelope (Extrema) Interpolation	operation (1 Ch in User selectable at 44Xi 5 GS/s 5 GS/s 200 GS/s User selectable fro 1,250,000 wavefo 1 ns 800 ns Max. Acquisition F 12.5M/25M 44Xi 200 ps (5 GS/s) Summed and cont From 8.5 to 11 bit	62Xi), (minimum rise ≥ 500 ms/div and ≤ 1 64Xi 5 GS/s 10 GS/s om 200 ps/div to 10 n rms/second Points (4 Ch/2 Ch, 2 C 64Xi 100 ps (10 GS/s) cinuous averaging to 1 s vertical resolution	time and amplitude re 00 kS/s 62Xi 5 GS/s 10 GS/s s/div h/1 Ch in 62Xi) 62Xi 100 ps (10 GS/s) million sweeps	104Xi 5 GS/s 10 GS/s User selectable fro Segments (Sequel 10,000) 104Xi	204Xi 5 GS/s 10 GS/s m 100 ps/div to 10 ns/div nce Mode) 204Xi
Acquisition System Single-Shot Sample Rate/Ch Interleaved Sample Rate (2 Ch) Random Interleaved Sampling (RIS) RIS Mode Trigger Rate (Maximum) Sequence Time Stamp Resolution Minimum Time Between Sequential Segments Acquisition Memory Options Standard Acquisition Processing Time Resolution (min, Single-shot) Averaging ERES Envelope (Extrema) Interpolation Trigger System	operation (1 Ch in User selectable at 44Xi 5 GS/s 5 GS/s 200 GS/s User selectable from 1,250,000 wavefor 1 ns 800 ns Max. Acquisition From 8.5 to 11 bit Envelope, floor, or Linear or (Sinx)/x	62Xi), (minimum rise ≥ 500 ms/div and ≤ 1 64Xi 5 GS/s 10 GS/s om 200 ps/div to 10 n rms/second Points (4 Ch/2 Ch, 2 C 64Xi 100 ps (10 GS/s) inuous averaging to 1 s vertical resolution roof for up to 1 million	time and amplitude re 00 kS/s 62Xi 5 GS/s 10 GS/s s/div h/1 Ch in 62Xi) 62Xi 100 ps (10 GS/s) million sweeps	104Xi 5 GS/s 10 GS/s User selectable fro Segments (Sequel 10,000) 104Xi	204Xi 5 GS/s 10 GS/s m 100 ps/div to 10 ns/div nce Mode) 204Xi
Acquisition System Single-Shot Sample Rate/Ch Interleaved Sample Rate (2 Ch) Random Interleaved Sampling (RIS) RIS Mode Trigger Rate (Maximum) Sequence Time Stamp Resolution Minimum Time Between Sequential Segments Acquisition Memory Options Standard Acquisition Processing Time Resolution (min, Single-shot) Averaging ERES Envelope (Extrema) Interpolation Trigger System Trigger Modes	operation (1 Ch in User selectable at 44Xi 5 GS/s 5 GS/s 200 GS/s User selectable from 1,250,000 wavefor 1 ns 800 ns Max. Acquisition From 8.5 to 11 bit Envelope, floor, or Linear or (Sinx)/x Normal, Auto, Sing	62Xi), (minimum rise ≥ 500 ms/div and ≤ 1 64Xi 5 GS/s 10 GS/s om 200 ps/div to 10 n rms/second Points (4 Ch/2 Ch, 2 C 64Xi 100 ps (10 GS/s) inuous averaging to 1 s vertical resolution roof for up to 1 million gle, Stop	time and amplitude re 00 kS/s 62Xi 5 GS/s 10 GS/s s/div h/1 Ch in 62Xi) 62Xi 100 ps (10 GS/s) million sweeps	104Xi 5 GS/s 10 GS/s User selectable from Segments (Sequent 10,000 104Xi 100 ps (10 GS/s)	204Xi 5 GS/s 10 GS/s m 100 ps/div to 10 ns/div nce Mode) 204Xi 100 ps (10 GS/s)
Acquisition System Single-Shot Sample Rate/Ch Interleaved Sample Rate (2 Ch) Random Interleaved Sampling (RIS) RIS Mode Trigger Rate (Maximum) Sequence Time Stamp Resolution Minimum Time Between Sequential Segments Acquisition Memory Options Standard Acquisition Processing Time Resolution (min, Single-shot) Averaging ERES Envelope (Extrema) Interpolation Trigger System Trigger Modes Sources	operation (1 Ch in User selectable at 44Xi 5 GS/s 5 GS/s 200 GS/s User selectable from 1,250,000 wavefor 1 ns 800 ns Max. Acquisition From 8.5 to 11 bit Envelope, floor, or Linear or (Sinx)/x Normal, Auto, Sing Any input channel	62Xi), (minimum rise ≥ 500 ms/div and ≤ 1 64Xi 5 GS/s 10 GS/s om 200 ps/div to 10 n rms/second Points (4 Ch/2 Ch, 2 C 64Xi 100 ps (10 GS/s) inuous averaging to 1 s vertical resolution roof for up to 1 million gle, Stop External, Ext/10, or I	time and amplitude re 00 kS/s 62Xi 5 GS/s 10 GS/s s/div h/1 Ch in 62Xi) 62Xi 100 ps (10 GS/s) million sweeps on sweeps	104Xi 5 GS/s 10 GS/s User selectable from Segments (Sequent 10,000 104Xi 100 ps (10 GS/s)	204Xi 5 GS/s 10 GS/s m 100 ps/div to 10 ns/div nce Mode) 204Xi 100 ps (10 GS/s)
Acquisition System Single-Shot Sample Rate/Ch Interleaved Sample Rate (2 Ch) Random Interleaved Sampling (RIS) RIS Mode Trigger Rate (Maximum) Sequence Time Stamp Resolution Minimum Time Between Sequential Segments Acquisition Memory Options Standard Acquisition Processing Time Resolution (min, Single-shot) Averaging ERES Envelope (Extrema) Interpolation Trigger System Trigger Modes Sources Trigger Coupling	operation (1 Ch in User selectable at 44Xi 5 GS/s 5 GS/s 200 GS/s User selectable from 1,250,000 wavefor 1 ns 800 ns Max. Acquisition From 8.5 to 11 bit Envelope, floor, or Linear or (Sinx)/x Normal, Auto, Sing Any input channel DC, AC (typically 7)	62Xi), (minimum rise ≥ 500 ms/div and ≤ 1 64Xi 5 GS/s 10 GS/s 200 ps/div to 10 n rms/second Points (4 Ch/2 Ch, 2 C 64Xi 100 ps (10 GS/s) inuous averaging to 1 s vertical resolution roof for up to 1 million gle, Stop External, Ext/10, or I 7.5 Hz), HF Reject, LF	time and amplitude re 00 kS/s 62Xi 5 GS/s 10 GS/s s/div 62Xi 100 ps (10 GS/s) million sweeps on sweeps Line; slope and level u Reject	104Xi 5 GS/s 10 GS/s User selectable from Segments (Sequent 10,000 104Xi 100 ps (10 GS/s)	204Xi 5 GS/s 10 GS/s m 100 ps/div to 10 ns/div nce Mode) 204Xi 100 ps (10 GS/s)
Acquisition System Single-Shot Sample Rate/Ch Interleaved Sample Rate (2 Ch) Random Interleaved Sampling (RIS) RIS Mode Trigger Rate (Maximum) Sequence Time Stamp Resolution Minimum Time Between Sequential Segments Acquisition Memory Options Standard Acquisition Processing Time Resolution (min, Single-shot) Averaging ERES Envelope (Extrema) Interpolation Trigger System Trigger Modes Sources Trigger Coupling Pre-trigger Delay	operation (1 Ch in User selectable at 44Xi 5 GS/s 5 GS/s 200 GS/s User selectable from 1,250,000 wavefor 1 ns 800 ns Max. Acquisition From 8.5 to 11 bit Envelope, floor, or Linear or (Sinx)/x Normal, Auto, Sing Any input channel DC, AC (typically 70–100% of memore	62Xi), (minimum rise ≥ 500 ms/div and ≤ 1 64Xi 5 GS/s 10 GS/s 200 ps/div to 10 n rms/second Points (4 Ch/2 Ch, 2 C 64Xi 100 ps (10 GS/s) inuous averaging to 1 s vertical resolution roof for up to 1 million gle, Stop External, Ext/10, or I 7.5 Hz), HF Reject, LF ry size (adjustable in	time and amplitude re 00 kS/s 62Xi 5 GS/s 10 GS/s s/div h/1 Ch in 62Xi) 62Xi 100 ps (10 GS/s) million sweeps on sweeps ine; slope and level u Reject 1% increments, or 100	104Xi 5 GS/s 10 GS/s User selectable fro Segments (Sequel 10,000 104Xi 100 ps (10 GS/s)	204Xi 5 GS/s 10 GS/s m 100 ps/div to 10 ns/div nce Mode) 204Xi 100 ps (10 GS/s) except Line
Acquisition System Single-Shot Sample Rate/Ch Interleaved Sample Rate (2 Ch) Random Interleaved Sampling (RIS) RIS Mode Trigger Rate (Maximum) Sequence Time Stamp Resolution Minimum Time Between Sequential Segments Acquisition Memory Options Standard Acquisition Processing Time Resolution (min, Single-shot) Averaging ERES Envelope (Extrema) Interpolation Trigger System Trigger Modes Sources Trigger Coupling Pre-trigger Delay Post-trigger Delay	operation (1 Ch in User selectable at 44Xi 5 GS/s 5 GS/s 200 GS/s User selectable from 1,250,000 wavefor 1 ns 800 ns Max. Acquisition From 8.5 to 11 bit 1 b	62Xi), (minimum rise ≥ 500 ms/div and ≤ 1 64Xi 5 GS/s 10 GS/s 200 ps/div to 10 n rms/second Points (4 Ch/2 Ch, 2 C 64Xi 100 ps (10 GS/s) inuous averaging to 1 s vertical resolution roof for up to 1 million gle, Stop External, Ext/10, or I 7.5 Hz), HF Reject, LF ry size (adjustable in ions in real time mod	time and amplitude re 00 kS/s 62Xi 5 GS/s 10 GS/s s/div h/1 Ch in 62Xi) 62Xi 100 ps (10 GS/s) million sweeps on sweeps cine; slope and level u Reject 1% increments, or 100 e, limited at slower time	104Xi 5 GS/s 10 GS/s User selectable fro Segments (Sequel 10,000 104Xi 100 ps (10 GS/s)	204Xi 5 GS/s 10 GS/s m 100 ps/div to 10 ns/div nce Mode) 204Xi 100 ps (10 GS/s) except Line
Acquisition System Single-Shot Sample Rate/Ch Interleaved Sample Rate (2 Ch) Random Interleaved Sampling (RIS) RIS Mode Trigger Rate (Maximum) Sequence Time Stamp Resolution Minimum Time Between Sequential Segments Acquisition Memory Options Standard Acquisition Processing Time Resolution (min, Single-shot) Averaging ERES Envelope (Extrema) Interpolation Trigger System Trigger Modes Sources Trigger Coupling Pre-trigger Delay Post-trigger Delay Hold-off	operation (1 Ch in User selectable at 44Xi 5 GS/s 5 GS/s 200 GS/s User selectable from 1,250,000 wavefor 1,250,000 wavefor 1 ns 800 ns Max. Acquisition From 8.5 to 11 bit 1	62Xi), (minimum rise ≥ 500 ms/div and ≤ 1 64Xi 5 GS/s 10 GS/s 200 ps/div to 10 n rms/second Points (4 Ch/2 Ch, 2 C 64Xi 100 ps (10 GS/s) inuous averaging to 1 s vertical resolution roof for up to 1 million roof for up to 1 million gle, Stop External, Ext/10, or I 7.5 Hz), HF Reject, LF ry size (adjustable in ions in real time mod to 1,000,000,000 even	time and amplitude re 00 kS/s 62Xi 5 GS/s 10 GS/s s/div h/1 Ch in 62Xi) 62Xi 100 ps (10 GS/s) million sweeps on sweeps cine; slope and level u Reject 1% increments, or 100 e, limited at slower time	104Xi 5 GS/s 10 GS/s User selectable fro Segments (Sequel 10,000 104Xi 100 ps (10 GS/s)	204Xi 5 GS/s 10 GS/s m 100 ps/div to 10 ns/div nce Mode) 204Xi 100 ps (10 GS/s) except Line
Acquisition System Single-Shot Sample Rate/Ch Interleaved Sample Rate (2 Ch) Random Interleaved Sampling (RIS) RIS Mode Trigger Rate (Maximum) Sequence Time Stamp Resolution Minimum Time Between Sequential Segments Acquisition Memory Options Standard Acquisition Processing Time Resolution (min, Single-shot) Averaging ERES Envelope (Extrema) Interpolation Trigger System Trigger Modes Sources Trigger Coupling Pre-trigger Delay Post-trigger Delay	operation (1 Ch in User selectable at 44Xi 5 GS/s 5 GS/s 200 GS/s User selectable from 1,250,000 wavefor 1 ns 800 ns Max. Acquisition From 8.5 to 11 bit 1 b	62Xi), (minimum rise ≥ 500 ms/div and ≤ 1 64Xi 5 GS/s 10 GS/s 200 ps/div to 10 n rms/second Points (4 Ch/2 Ch, 2 C 64Xi 100 ps (10 GS/s) inuous averaging to 1 s vertical resolution roof for up to 1 million roof for up to 1 million gle, Stop External, Ext/10, or I 7.5 Hz), HF Reject, LF ry size (adjustable in ions in real time mod to 1,000,000,000 even	time and amplitude re 00 kS/s 62Xi 5 GS/s 10 GS/s s/div h/1 Ch in 62Xi) 62Xi 100 ps (10 GS/s) million sweeps on sweeps cine; slope and level u Reject 1% increments, or 100 e, limited at slower time	104Xi 5 GS/s 10 GS/s User selectable fro Segments (Sequel 10,000 104Xi 100 ps (10 GS/s)	204Xi 5 GS/s 10 GS/s m 100 ps/div to 10 ns/div nce Mode) 204Xi 100 ps (10 GS/s) except Line

Trigger System (cont'd)	44Xi	64Xi	62Xi	104Xi	204Xi
Trigger Sensitivity with Edge Trigger	2 div @ < 400 MHz	2 div @ < 600 MHz	2 div @ < 600 MHz	2 div @ < 1 GHz	2 div @ < 2 GHz
(Ch 1–4 + external, DC, AC, and LFrej coupling)	1 div @ < 200 MHz	1 div @ < 200 MHz	1 div @ < 200 MHz	1 div @ < 200 MHz	1 div @ < 200 MHz
Max. Trigger Frequency with SMART Trigger™ (Ch 1-4 + external)	400 MHz @ ≥ 10 mV	600 MHz @ ≥ 10 mV	600 MHz @ ≥ 10 mV	1 GHz @ ≥ 10 mV	2 GHz @ ≥ 10 mV
External Trigger Range	EXT/10 ±4 V; EXT ±	400 mV			
Basic Triggers					
Edge	Triggers when signa	al meets slope (positiv	e, negative, or Windo	w) and level condition	١.
SMART Triggers					
State or Edge Qualified		ut source only if a defi		curred on another inpu	it source.
Dropout		pps out for longer than			
Pattern	on WaveRunner 62) selected independe	AND, NAND, OR, NO Xi). Each source can b ntly. Triggers at start o	e high, low, or don't or or end of the pattern.	care. The High and Lo	w level can be
TV-Composite Video		fields (1, 2, 4, or 8), Pondard video (up to 150		pe, or Line (up to 150	00), for NTSC, PAL,
SMART Triggers with Exclusion	Technology				
Glitch and Pulse Width		or negative glitches v ndwidth limit of oscill		from 500 ps to 20 s	or on intermittent
Signal or Pattern Interval		s selectable between			
Timeout (State/Edge Qualified)	Triggers on any source if a given state (or transition edge) has occurred on another source. Delay between sources is 1 ns to 20 s, or 1 to 99,999,999 events.				
Runt	Trigger on positive of 1 ns and 20 s.	or negative runts defir	ed by two voltage lim	nits and two time limit	ts. Select between
Slew Rate	Trigger on edge rates. Select limits for dV, dt, and slope. Select edge limits between 1 ns and 20 s.				
Exclusion Triggering	Trigger on intermitte	ent faults by specifying	g the normal width or	period.	
LeCroy WaveStream Fast Viewi	ng Mode				
Intensity	256 Intensity Levels	s, 1–100% adjustable	via front panel control		
Number of Channels	up to 4 simultaneou				
Max Sampling Rate		WaveRunner 62Xi, 64	Xi, 104Xi, 204Xi in int	erleaved mode)	
Waveforms/second (continuous)	up to 8000 wavefor		1 11 0	\\\\ C\\	
Operation	Front panel toggle b	oetween normal real-ti	me mode and LeCroy	vvaveStream Fast Vi	ewing mode
Automatic Setup					
Auto Setup		imebase, trigger, and			
Vertical Find Scale	Automatically sets t maximum dynamic	the vertical sensitivity range.	and offset for the sele	ected channels to disp	olay a waveform with
Probes	44Xi	64Xi	62Xi	104Xi	204Xi
Probes	One PP008 per cha Optional passive an	nnel standard; d active probes availa	ole.	One PP007 per char Optional passive and	nnel standard; active probes available
Probe System; ProBus		ts and supports a vari		bes.	
Scale Factors	Automatically or ma	inually selected, depe	nding on probe used		
Color Waveform Display					
Type		el TFT-LCD with high r			
Resolution		xels; maximum exterr			
Number of Traces		of 8 traces. Simultan		l, zoom, memory, and	l math traces.
Grid Styles		Quad, Octal, XY, Singl			
Waveform Styles	Sample dots joined	or dots only in real-tin	ne mode		

Zoom Expansion Traces	5: 1				
	Display up to	4 Zoom/Math traces	vith 16 bits/data poir	nt	
Internal Waveform Memory					
•	M1, M2, M3,	M4 Internal Waveform	n Memory (store full	-length waveform with	16 bits/data point)
		umber of files limited			
Setup Storage					
Front Panel and Instrument Status	Store to the in	nternal hard drive, ove	r the network, or to	a USB-connected perip	heral device.
Interface					
Remote Control	Via Windows	Automation, or via Le	Crov Remote Comm	and Set	
GPIB Port (Accessory)	Supports IEEE				
Ethernet Port	10/100/1000B	Sase-T Ethernet interfa	ce (RJ-45 connector)		
JSB Ports	5 USB 2.0 por	rts (one on front of ins	strument) supports V	Vindows-compatible de	vices.
External Monitor Port	Standard 15-p	in D-Type SVGA-com	patible DB-15; conne	ct a second monitor to	use
		ktop display mode wi			
Serial Port	DB-9 RS-232	port (not for remote o	scilloscope control)		
Auxiliary Input	44Xi	64Xi	62Xi	104Xi	204Xi
Signal Types		n External Trigger or E	kternal Clock input o	n front panel	
Coupling		/Ω: AC, DC, GND			
Maximum Input Voltage		1 MΩ: 400 V max.			1 MΩ: 250 V max.
	(DC + Peak A	C ≤ 5 KHZ)		(DC + Peak A	C ≤ 10 KHz)
Auxiliary Output					
Signal Type	Trigger Enable	ed, Trigger Output. Pa	ss/Fail, or Off		
Output Level	TTL, ≈3.3 V				
Connector Type	BNC, located	on rear panel			
General					
Auto Calibration	Ensures spec	ified DC and timing ac	curacy is maintained	for 1 year minimum.	
Calibrator	Output availab	ole on front panel con	nector provides a var	iety of signals for probe	e calibration
	and compens				
Power Requirements		ntegory: 300V CAT II; I		utomatic AC Voltage Se ption: 340 VA/340 W; 2	
Environmental					
Temperature: Operating	+5 °C to +40	°C			
Temperature: Non-Operating	-20 °C to +60				
Humidity: Operating	Maximum rela	ative humidity 80% fo	r temperatures up to	31 °C decreasing linea	rly
		ve humidity at 40 °C	· · · · · · · · · · · · · · · · · · ·		
Humidity: Non-Operating		H (non-condensing) a	s tested per MIL-PRF	-28800F	
Altitude: Operating	Up to 2,000 n	<u>1</u>			
Altitude: Non-Operating	12,190 m				
Physical					
Dimensions (HWD)	260 mm x 340) mm x 152 mm Exc	luding accessories ar	nd projections (10.25" x	13.4" x 6")
Net Weight	6.95 kg. (15.5	lbs.)			
Certifications					
		, UL and cUL listed; C 2 No. 61010-1-04.	onforms to EN 6132	6, EN 61010-1, UL 610	10-1 2nd Edition,
Warranty and Service					
Training and Corvice	3-vear warran	tv. calibration recomp	nended annually. Ont	ional service programs	include extended
		rades, calibration, and			morado oxtoriada

Ordering Information

Product Description	Product Code
WaveRunner Xi Series Oscilloscopes	
2 GHz, 4 Ch, 5 GS/s, 12.5 Mpts/Ch (10 GS/s, 25 Mpts/Ch in interleaved mode) with 10.4" Color Touch Screen Display	WaveRunner 204Xi
1 GHz, 4 Ch, 5 GS/s, 12.5 Mpts/Ch (10 GS/s, 25 Mpts/Ch in interleaved mode) with 10.4" Color Touch Screen Display	WaveRunner 104Xi
600 MHz, 4 Ch, 5 GS/s, 12.5 Mpts/Ch (10 GS/s, 25 Mpts/Ch in interleaved mode) with 10.4" Color Touch Screen Display	WaveRunner 64Xi
600 MHz, 2 Ch, 5 GS/s, 12.5 Mpts/Ch (10 GS/s, 25 Mpts/Ch in interleaved mode) with 10.4" Color Touch Screen Display	WaveRunner 62Xi
400 MHz, 4 Ch, 5 GS/s, 12.5 Mpts/Ch (25 Mpts/Ch in interleaved mode)	WaveRunner 44Xi

Included with Standard Configuration

with 10.4" Color Touch Screen Display

General Purpose Software Options

Statistics Software Package	WRXi-STAT
Master Analysis Software Package	WRXi-XMAP
Advanced Math Software Package	WRXi-XMATH
Intermediate Math Software Package	WRXi-XWAV
Value Analysis Software Package (Includes XWAV and JTA2) WRXi-XVAP
Advanced Customization Software Package	WRXi-XDEV
Processing Web Editor Software Package	WRXi-XWEB
HDTV Trigger for 1080i, 1080p and 720p Formats	WRXi-HDTV-TRIG

Application Specific Software Options

Jitter and Timing Analysis Software Package	WRXi-JTA2
Digital Filter Software Package	WRXi-DFP2
Disk Drive Measurement Software Package	WRXi-DDM2
PowerMeasure Analysis Software Package	WRXi-PMA2
Serial Data Mask Software Package	WRXi-SDM
USB 2.0 Compliance Test Software Package	WRXi-USB2
EMC Pulse Parameter Software Package	WRXi-EMC
Electrical Telecom Mask Test Package	ET-PMT

Serial Data Options

I ² C Trigger and Decode Option	WRXi-I2Cbus TD
SPI Trigger and Decode Option	WRXi-SPIbus TD
UART and RS-232 Trigger and Decode Option	WRXi-UART-RS232bus TD
CANbus TD Trigger and Decode Option	CANbus TD
CANbus TDM Trigger, Decode, and Measure/Grap	h Option CANbus TDM

Product Description Product Code

Serial Data Options (cont'd)

LIN Trigger and Decode Option	WRXi-LINbus TD
FlexRay Trigger and Decode Option	WRXi-FlexRaybus TD

A variety of Vehicle Bus Analyzers based on the WaveRunner Xi platform are available. These units are equipped with a Symbolic CAN trigger and decode.

Mixed Signal Oscilloscope Options

500 MHz, 18 Channels, 2 GS/s, 50 Mpts/Ch	MS-500
Mixed Signal Oscilloscope Option	
250 MHz, 36 Ch, 1 GS/s, 25 Mpts/Ch	MS-500-36
(500 MHz, 18 Ch, 2 GS/s, 50 Mpts/Ch Interleaved)	
Mixed Signal Oscilloscope Option	
250 MHz, 18 Channels, 1 GS/s, 10 Mpts/Ch	MS-250
Mixed Signal Oscilloscope Option	

Probes and Amplifiers*

Set of 4 ZS1500, 1.5 GHz, 0.9 pF, 1 MΩ ZS1500	-QUADPAK
High Impedance Active Probe	
Set of 4 ZS1000, 1 GHz, 0.9 pF, 1 MΩ ZS1000	-QUADPAK
High Impedance Active Probe	
2.5 GHz, 0.7 pF Active Probe	HFP2500
1 GHz Active Differential Probe (÷1, ÷10, ÷20)	AP034
500 MHz Active Differential Probe (x10, ÷1, ÷10, ÷100)	AP033
30 A; 100 MHz Current Probe – AC/DC; 30 A _{rms} ; 50 A _{rms} Pulse	CP031
30 A; 50 MHz Current Probe – AC/DC; 30 A _{rms} ; 50 A _{rms} Pulse	CP030
30 A; 50 MHz Current Probe – AC/DC; 30 A _{rms} ; 50 A _{peak} Pulse	AP015
150 A; 10 MHz Current Probe – AC/DC; 150 A _{rms} ; 500 A _{peak} Pulse	e CP150
500 A; 2 MHz Current Probe – AC/DC; 500 A _{rms} ; 700 A _{peak} Pulse	CP500
1,400 V, 100 MHz High-Voltage Differential Probe	ADP305
1,400 V, 20 MHz High-Voltage Differential Probe	ADP300
1 Ch, 100 MHz Differential Amplifier	DA1855A

^{*}A wide variety of other passive, active, and differential probes are also available. Consult LeCroy for more information.

Hardware Accessories

WS-GPIB
WRXi-SOFTCASE
WRXi-HARDCASE
WRXi-MS-CLAMP
WRXi-RACK
WRXi-KYBD
WRXi-RHD
WRXi-RHD-02

A variety of local language front panel overlays are also available.

Customer Service

LeCroy oscilloscopes and probes are designed, built, and tested to ensure high reliability. In the unlikely event you experience difficulties, our digital oscilloscopes are fully warranted for three years, and our probes are warranted for one year.

This warranty includes:

- No charge for return shipping
- Long-term 7-year support
- Upgrade to latest software at no charge



Local sales offices are located throughout the world. To find the most convenient one visit www.lecroy.com